



Issue Classification 	Application No.	Applicant(s)	
	09/917,637	HATANO ET AL.	
	Examiner	Art Unit	
	Patrick J. Lee	2878	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
250		216		250	201.5				
INTERNATIONAL CLASSIFICATION				359	656				
H	0	1	J	3/14	369	112.01			
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				/					
Patrick J. Lee (Assistant Examiner) (Date)				 DAVID PORTA SUPERVISORY PATENT EXAMINER (Patent Examiner) (Date) 12/17/03 TECHNOLOGY CENTER 2800				Total Claims Allowed: 56	
(Legal Instruments Examiner) (Date)								O.G. Print Claim(s) 28	O.G. Print Fig. 1

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant										<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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